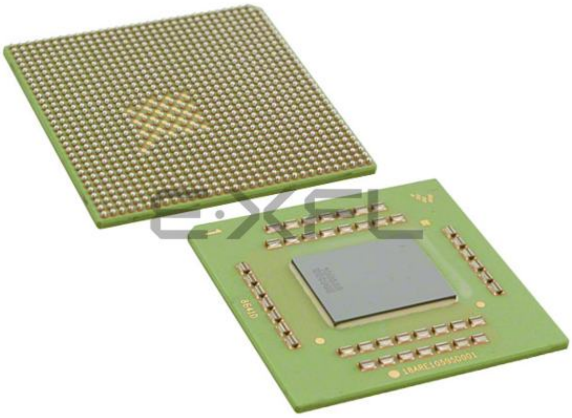
NXP USA Inc. - MC8641VJ1333JE Datasheet



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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e600
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.333GHz
Co-Processors/DSP	-
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	994-BCBGA, FCCBGA
Supplier Device Package	994-FCCBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc8641vj1333je

2 Electrical Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC8641. The MPC8641 is currently targeted to these specifications.

2.1 Overall DC Electrical Characteristics

This section covers the ratings, conditions, and other characteristics.

2.1.1 Absolute Maximum Ratings

Table 1 provides the absolute maximum ratings.

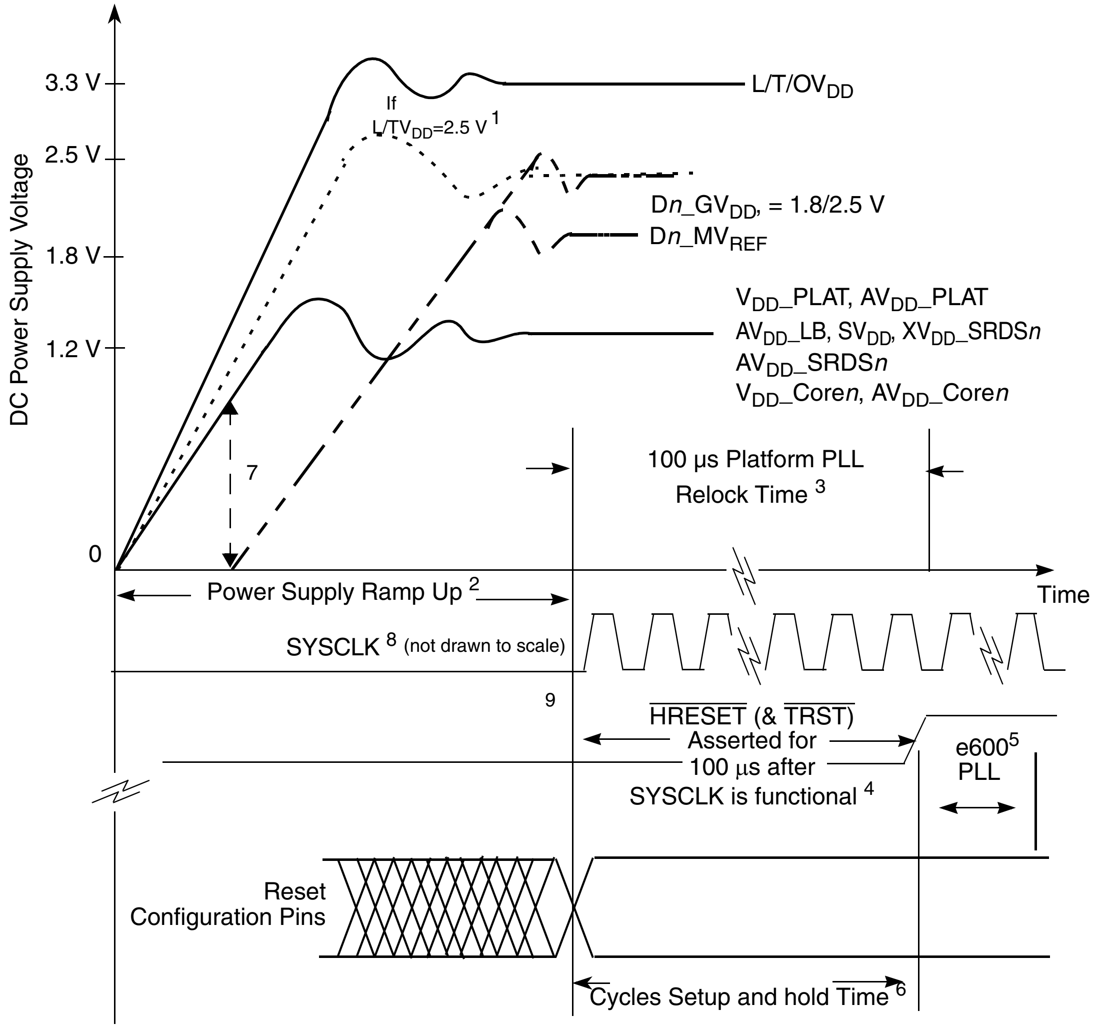
Table 1. Absolute Maximum Ratings[1]

Characteristic	Symbol	Absolute Maximum Value	Unit	Notes
Cores supply voltages	V_{DD}_Core0, V_{DD}_Core1	–0.3 to 1.21 V	V	2
Cores PLL supply	AV_{DD}_Core0, AV_{DD}_Core1	–0.3 to 1.21 V	V	—
SerDes Transceiver Supply (Ports 1 and 2)	SV_{DD}	–0.3 to 1.21 V	V	—
SerDes Serial I/O Supply Port 1	XV_{DD}_SRDS1	–0.3 to 1.21V	V	—
SerDes Serial I/O Supply Port 2	XV_{DD}_SRDS2	–0.3 to 1.21 V	V	—
SerDes DLL and PLL supply voltage for Port 1 and Port 2	AV_{DD}_SRDS1, AV_{DD}_SRDS2	–0.3 to 1.21V	V	—
Platform Supply voltage	V_{DD}_PLAT	–0.3 to 1.21V	V	—
Local Bus and Platform PLL supply voltage	AV_{DD}_LB, AV_{DD}_PLAT	–0.3 to 1.21V	V	—
DDR and DDR2 SDRAM I/O supply voltages	D1_GV_{DD}, D2_GV_{DD}	–0.3 to 2.75 V	V	3
		–0.3 to 1.98 V	V	3
eTSEC 1 and 2 I/O supply voltage	LV_{DD}	–0.3 to 3.63 V	V	4
		–0.3 to 2.75 V	V	4
eTSEC 3 and 4 I/O supply voltage	TV_{DD}	–0.3 to 3.63 V	V	4
		–0.3 to 2.75 V	V	4
Local Bus, DUART, DMA, Multiprocessor Interrupts, System Control & Clocking, Debug, Test, Power management, I^2C, JTAG and Miscellaneous I/O voltage	OV_{DD}	–0.3 to 3.63 V	V	—

Table 2. Recommended Operating Conditions (continued)

Characteristic		Symbol	Recommended Value	Unit	Notes
SerDes Serial I/O Supply Port 1		XV_{DD}_SRDS1	1.10 ± 50 mV	V	8
			1.05 ± 50 mV		7
SerDes Serial I/O Supply Port 2		XV_{DD}_SRDS2	1.10 ± 50 mV	V	8
			1.05 ± 50 mV		7
SerDes DLL and PLL supply voltage for Port 1 and Port 2		AV_{DD}_SRDS1, AV_{DD}_SRDS2	1.10 ± 50 mV	V	8
			1.05 ± 50 mV		7
Platform Supply voltage		V_{DD}_PLAT	1.10 ± 50 mV	V	8
			1.05 ± 50 mV		7
Local Bus and Platform PLL supply voltage		AV_{DD}_LB, AV_{DD}_PLAT	1.10 ± 50 mV	V	8
			1.05 ± 50 mV		7
DDR and DDR2 SDRAM I/O supply voltages		D1_$GV_{DD,}$ D2_GV_{DD}	2.5 V ± 125 mV	V	9
			1.8 V ± 90 mV	V	9
eTSEC 1 and 2 I/O supply voltage		LV_{DD}	3.3 V ± 165 mV	V	10
			2.5 V ± 125 mV	V	10
eTSEC 3 and 4 I/O supply voltage		TV_{DD}	3.3 V ± 165 mV	V	10
			2.5 V ± 125 mV	V	10
Local Bus, DUART, DMA, Multiprocessor Interrupts, System Control & Clocking, Debug, Test, Power management, I^2C, JTAG and Miscellaneous I/O voltage		OV_{DD}	3.3 V ± 165 mV	V	5
Input voltage	DDR and DDR2 SDRAM signals	D*n*_MV_{IN}	GND to D*n*_GV_{DD}	V	3, 6
	DDR and DDR2 SDRAM reference	D*n*_MV_{REF}	D*n*_GV_{DD}/2 ± 1%	V	
	Three-speed Ethernet signals	LV_{IN} TV_{IN}	GND to LV_{DD} GND to TV_{DD}	V	4, 6
	DUART, Local Bus, DMA, Multiprocessor Interrupts, System Control & Clocking, Debug, Test, Power management, I^2C, JTAG and Miscellaneous I/O voltage	OV_{IN}	GND to OV_{DD}	V	5,6

Figure 3 illustrates the Power Up sequence as described above.



Notes:

1. Dotted waveforms correspond to optional supply values for a specified power supply. See Table 2.
2. The recommended maximum ramp up time for power supplies is 20 milliseconds.
3. Refer to Section 5, “RESET Initialization” for additional information on PLL relock and reset signal assertion timing requirements.
4. Refer to Table 11 for additional information on reset configuration pin setup timing requirements. In addition see Figure 68 regarding $\overline{\text{HRESET}}$ and JTAG connection details including $\overline{\text{TRST}}$.
5. e600 PLL relock time is 100 microseconds maximum plus 255 MPX_clk cycles.
6. Stable PLL configuration signals are required as stable SYSCLK is applied. All other POR configuration inputs are required 4 SYSCLK cycles before $\overline{\text{HRESET}}$ negation and are valid at least 2 SYSCLK cycles after $\overline{\text{HRESET}}$ has negated (hold requirement). See Section 5, “RESET Initialization” for more information on setup and hold time of reset configuration signals.
7. V_{DD}_PLAT, AV_{DD}_PLAT must strictly reach 90% of their recommended voltage before the rail for D*n*_GV_{DD}, and D*n*_MV_{REF} reaches 10% of their recommended voltage.
8. SYSCLK must be driven only AFTER the power for the various power supplies is stable.
9. In device sleep mode, the reset configuration signals for DRAM types (TSEC2_TXD[4],TSEC2_TX_ER) must be valid BEFORE $\overline{\text{HRESET}}$ is asserted.

Figure 3. MPC8641 Power-Up and Reset Sequence

Table 21. DDR SDRAM Output AC Timing Specifications (continued)

At recommended operating conditions.

Parameter	Symbol [1]	Min	Max	Unit	Notes
$\overline{\text{MCS}}$[n] output hold with respect to MCK	t_{DDKHCX}			ns	3
600 MHz		1.10	—		7
533 MHz		1.48	—		7
400 MHz		1.95	—		
MCK to MDQS Skew	t_{DDKHMH}	–0.6	0.6	ns	4
MDQ/MECC/MDM output setup with respect to MDQS	t_{DDKHDS}, t_{DDKLDS}			ps	5
600 MHz		500	—		7
533 MHz		590	—		7
400 MHz		700	—		
MDQ/MECC/MDM output hold with respect to MDQS	t_{DDKHDX}, t_{DDKLDX}			ps	5
600 MHz		500	—		7
533 MHz		590	—		7
400 MHz		700	—		
MDQS preamble start	t_{DDKHMP}	$-0.5 \times t_{MCK} - 0.6$	$-0.5 \times t_{MCK} + 0.6$	ns	6

Table 29. GMII Receive AC Timing Specifications (continued)

At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5% and 2.5 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
RX_CLK clock fall time (80%-20%)	t_{GRXF}[2]	—	—	1.0	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{GRDVKH} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{RX} clock reference (K) going to the high state (H) or setup time. Also, t_{GRDXKL} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{GRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GRX} represents the GMII (G) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Guaranteed by design.
3. ±100 ppm tolerance on RX_CLK frequency

Figure 11 provides the AC test load for eTSEC.

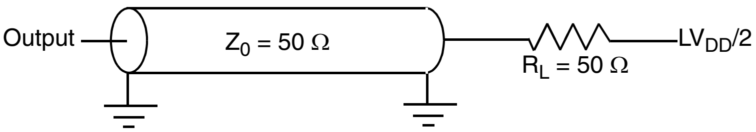


Figure 11. eTSEC AC Test Load

Figure 12 shows the GMII receive AC timing diagram.

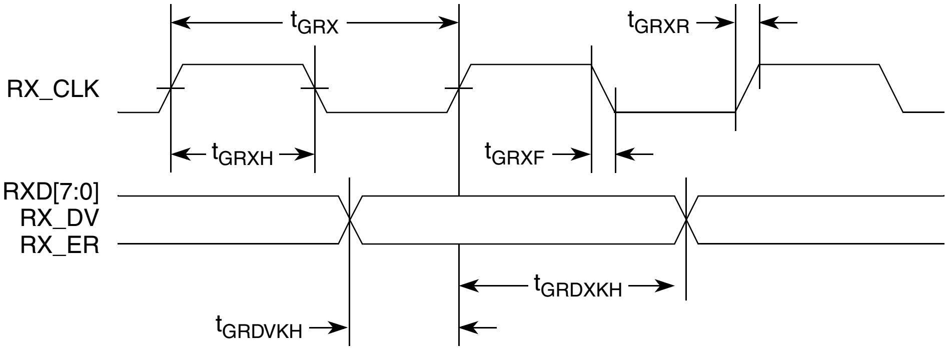


Figure 12. GMII Receive AC Timing Diagram

8.2.3.2 MII Receive AC Timing Specifications

Table 31 provides the MII receive AC timing specifications.

Table 31. MII Receive AC Timing Specifications

At recommended operating conditions with L/TV$_{DD}$ of 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}[2,3]	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}[3]	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise time (20%-80%)	t_{MRXR}[2]	1.0	—	4.0	ns
RX_CLK clock fall time (80%-20%)	t_{MRXF}[2]	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Guaranteed by design.
3. ±100 ppm tolerance on RX_CLK frequency

Figure 14 provides the AC test load for eTSEC.

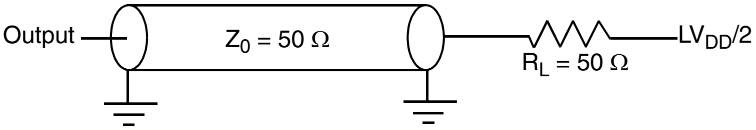


Figure 14. eTSEC AC Test Load

Figure 15 shows the MII receive AC timing diagram.

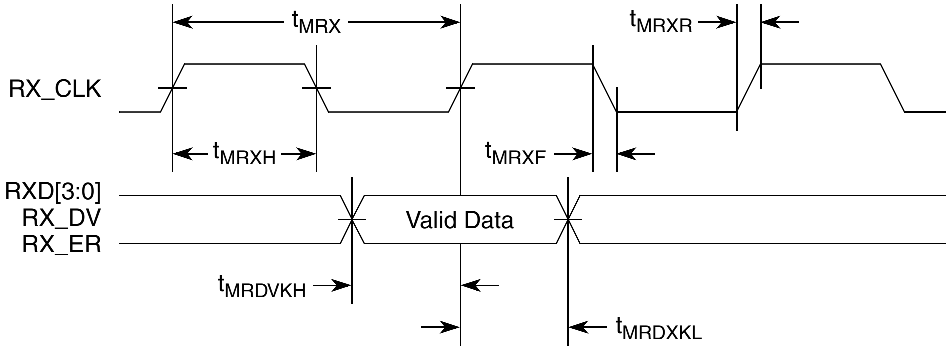


Figure 15. MII Receive AC Timing Diagram

Table 35. RGMII and RTBI AC Timing Specifications (continued)

At recommended operating conditions with L/TV_{DD} of 2.5 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
Clock period duration [3]	t_{RGT}[5,6]	7.2	8.0	8.8	ns
Duty cycle for 10BASE-T and 100BASE-TX [3, 4]	t_{RGTH}/t_{RGT}[5]	40	50	60	%
Rise time (20%–80%)	t_{RGTR}[5]	—	—	0.75	ns
Fall time (80%–20%)	t_{RGTF}[5]	—	—	0.75	ns

Notes:

1. Note that, in general, the clock reference symbol representation for this section is based on the symbols RGT to represent RGMII and RTBI timing. For example, the subscript of t_{RGT} represents the TBI (T) receive (RX) clock. Note also that the notation for rise (R) and fall (F) times follows the clock symbol that is being represented. For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (RGT).
2. This implies that PC board design will require clocks to be routed such that an additional trace delay of greater than 1.5 ns will be added to the associated clock signal.
3. For 10 and 100 Mbps, t_{RGT} scales to 400 ns ± 40 ns and 40 ns ± 4 ns, respectively.
4. Duty cycle may be stretched/shrunk during speed changes or while transitioning to a received packet's clock domains as long as the minimum duty cycle is not violated and stretching occurs for no more than three t_{RGT} of the lowest speed transitioned between.
5. Guaranteed by characterization
6. ±100 ppm tolerance on RX_CLK frequency

Figure 19 shows the RGMII and RTBI AC timing and multiplexing diagrams.

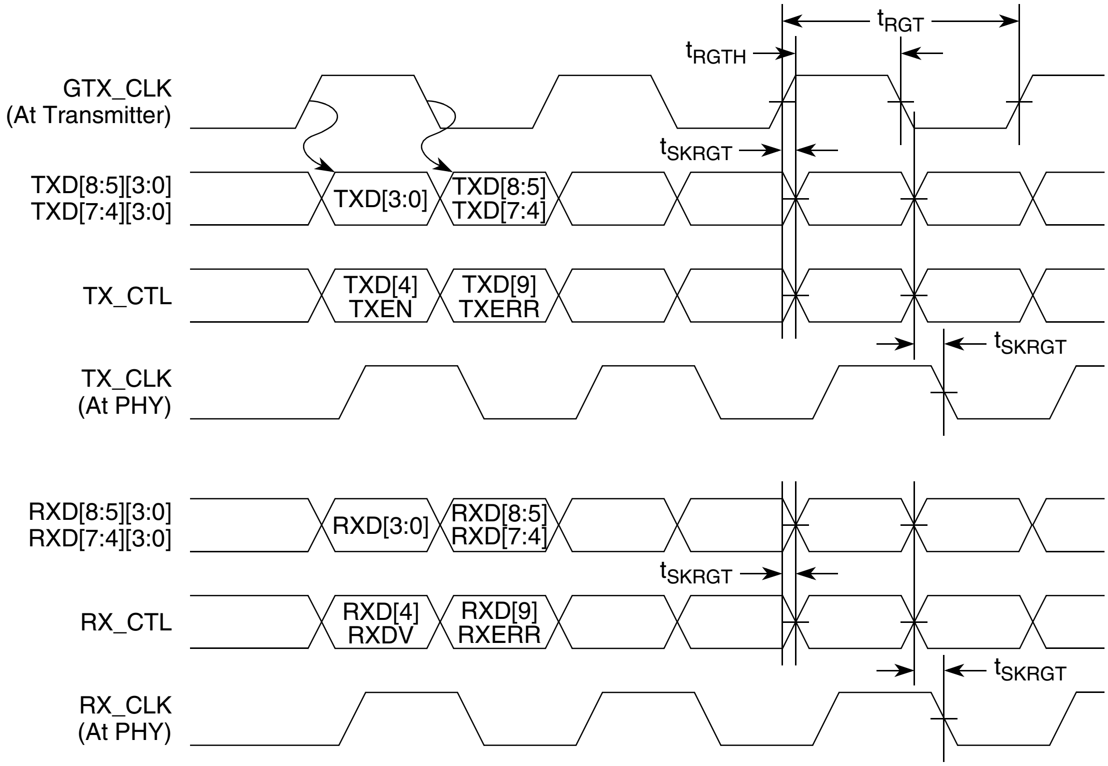


Figure 19. RGMII and RTBI AC Timing and Multiplexing Diagrams

Table 41. Local Bus Timing Parameters (OV_{DD} = 3.3 V)m - PLL Enabled (continued)

Parameter	Symbol [1]	Min	Max	Unit	Notes
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	2.3	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.7	—	ns	—
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.7	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.5	ns	5
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.5	ns	5

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(First two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(First two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
3. All signals are measured from $OV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times OV_{DD}$ of the signal in question for 3.3-V signaling levels.
4. Input timings are measured at the pin.
5. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
7. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
8. Guaranteed by design.

Figure 25 provides the AC test load for the local bus.

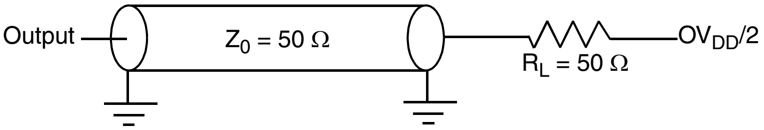


Figure 25. Local Bus AC Test Load

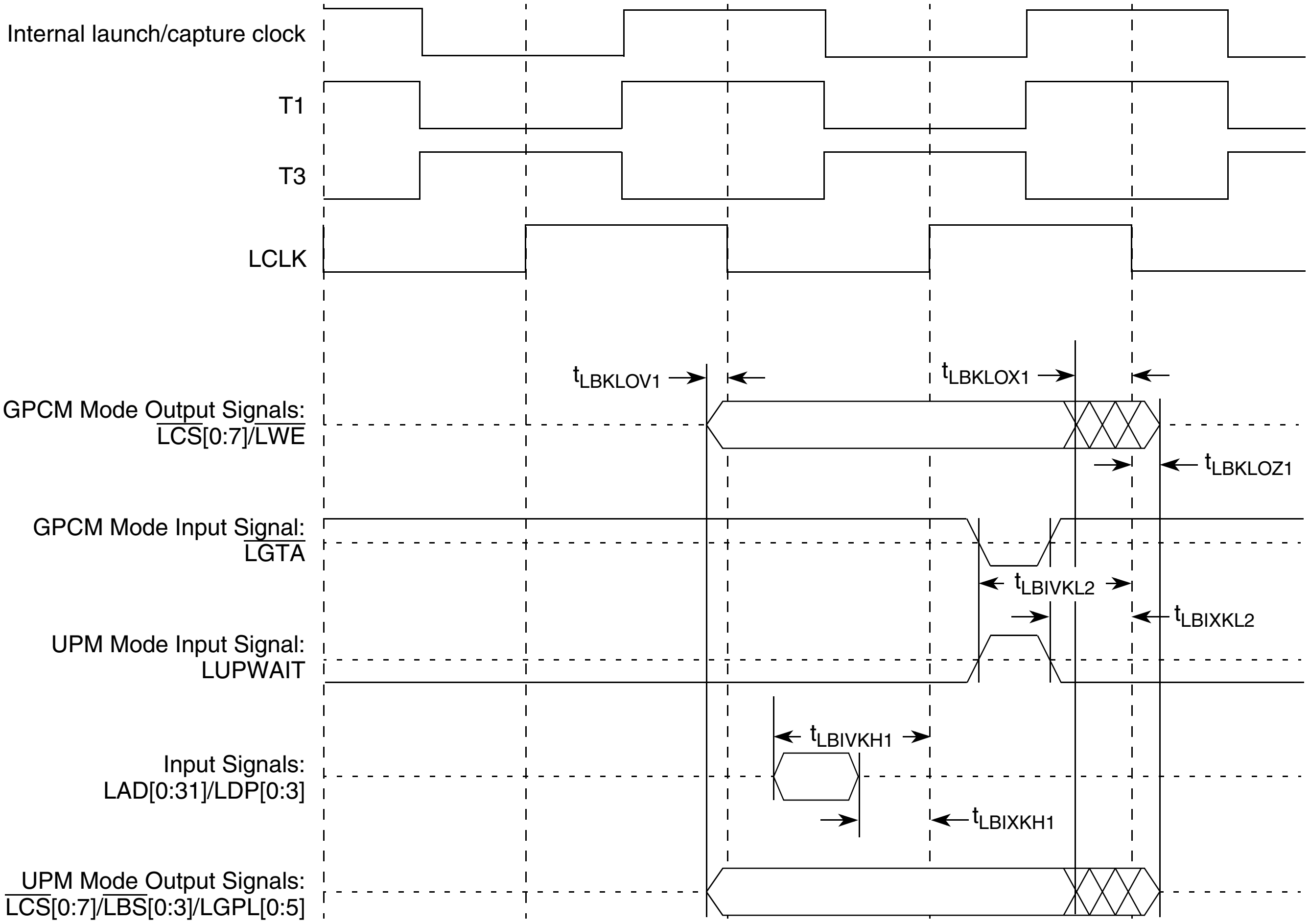


Figure 29. Local Bus Signals, GPCM/UPM Signals for LCRR[CLKDIV] = 2 (clock ratio of 4) (PLL Bypass Mode)

13.2.3 Interfacing With Other Differential Signaling Levels

With on-chip termination to SGND, the differential reference clocks inputs are HCSL (High-Speed Current Steering Logic) compatible DC-coupled.

Many other low voltage differential type outputs like LVDS (Low Voltage Differential Signaling) can be used but may need to be AC-coupled due to the limited common mode input range allowed (100 to 400 mV) for DC-coupled connection.

LVPECL outputs can produce signal with too large amplitude and may need to be DC-biased at clock driver output first, then followed with series attenuation resistor to reduce the amplitude, in addition to AC-coupling.

NOTE

Figure 43 to Figure 46 below are for conceptual reference only. Due to the fact that clock driver chip's internal structure, output impedance and termination requirements are different between various clock driver chip manufacturers, it is very possible that the clock circuit reference designs provided by clock driver chip vendor are different from what is shown below. They might also vary from one vendor to the other. Therefore, Freescale Semiconductor can neither provide the optimal clock driver reference circuits, nor guarantee the correctness of the following clock driver connection reference circuits. The system designer is recommended to contact the selected clock driver chip vendor for the optimal reference circuits with the MPC8641D SerDes reference clock receiver requirement provided in this document.

MPC8641D SerDes reference clock input's DC requirement, AC-coupling has to be used. Figure 45 assumes that the LVPECL clock driver's output impedance is 50 Ω. R1 is used to DC-bias the LVPECL outputs prior to AC-coupling. Its value could be ranged from 140 Ω to 240 Ω depending on clock driver vendor's requirement. R2 is used together with the SerDes reference clock receiver's 50-Ω termination resistor to attenuate the LVPECL output's differential peak level such that it meets the MPC8641D SerDes reference clock's differential input amplitude requirement (between 200 mV and 800 mV differential peak). For example, if the LVPECL output's differential peak is 900 mV and the desired SerDes reference clock input amplitude is selected as 600mV, the attenuation factor is 0.67, which requires R2 = 25 Ω. Please consult clock driver chip manufacturer to verify whether this connection scheme is compatible with a particular clock driver chip.

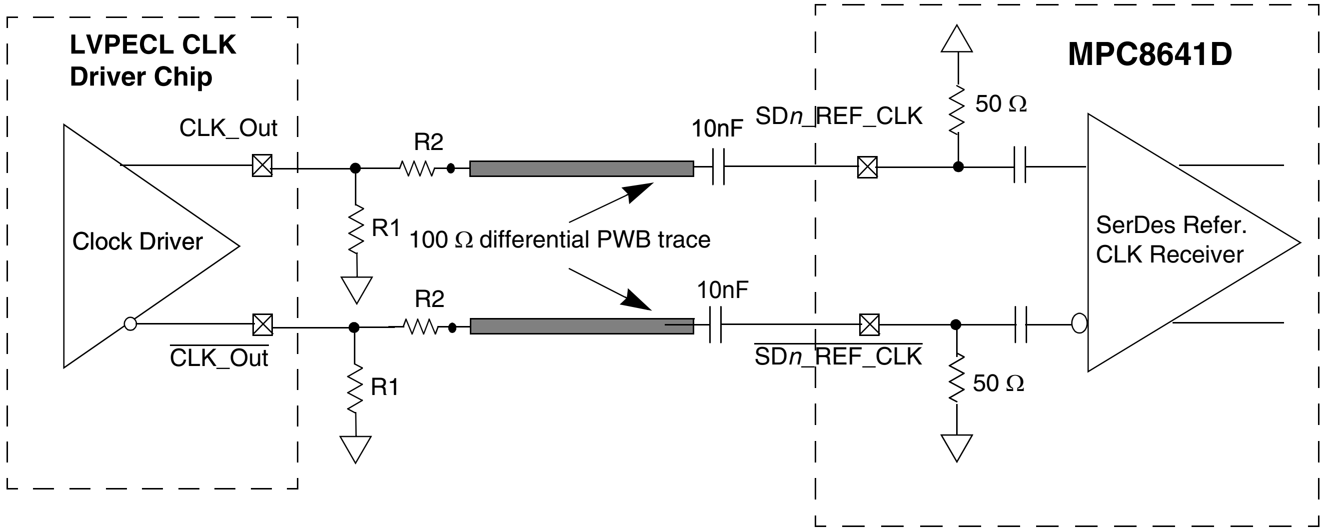


Figure 45. AC-Coupled Differential Connection with LVPECL Clock Driver (Reference Only)

14.4.3 Differential Receiver (RX) Input Specifications

Table 50 defines the specifications for the differential input at all receivers (RXs). The parameters are specified at the component pins.

Table 50. Differential Receiver (RX) Input Specifications

Symbol	Parameter	Min	Nom	Max	Units	Comments
UI	Unit Interval	399.88	400	400.12	ps	Each UI is 400 ps ± 300 ppm. UI does not account for Spread Spectrum Clock dictated variations. See Note 1.
$V_{RX\text{-}DIFFp\text{-}p}$	Differential Peak-to-Peak Output Voltage	0.175	—	—	V	$V_{RX\text{-}DIFFp\text{-}p} = 2*\lvert V_{RX\text{-}D+} - V_{RX\text{-}D-}\rvert$ See Note 2.
$T_{RX\text{-}EYE}$	Minimum Receiver Eye Width	0.4	—	—	UI	The maximum interconnect media and Transmitter jitter that can be tolerated by the Receiver can be derived as $T_{RX\text{-}MAX\text{-}JITTER} = 1 - T_{RX\text{-}EYE} = 0.6$ UI. See Notes 2 and 3.
$T_{RX\text{-}EYE\text{-}MEDIAN\text{-}to\text{-}MAX\text{-}JITTER}$	Maximum time between the jitter median and maximum deviation from the median.	—	—	0.3	UI	Jitter is defined as the measurement variation of the crossing points ($V_{RX\text{-}DIFFp\text{-}p} = 0$ V) in relation to a recovered TX UI. A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. Jitter is measured using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI. See Notes 2, 3 and 7.
$V_{RX\text{-}CM\text{-}ACp}$	AC Peak Common Mode Input Voltage	—	—	150	mV	$V_{RX\text{-}CM\text{-}ACp} = \lvert V_{RXD+} - V_{RXD-}\rvert/2 - V_{RX\text{-}CM\text{-}DC}$ $V_{RX\text{-}CM\text{-}DC} = DC_{(avg)}$ of $\lvert V_{RX\text{-}D+} - V_{RX\text{-}D-}\rvert/2$ See Note 2
$RL_{RX\text{-}DIFF}$	Differential Return Loss	15	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D– lines biased at +300 mV and –300 mV, respectively. See Note 4
$RL_{RX\text{-}CM}$	Common Mode Return Loss	6	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D– lines biased at 0 V. See Note 4
$Z_{RX\text{-}DIFF\text{-}DC}$	DC Differential Input Impedance	80	100	120	Ω	RX DC Differential mode impedance. See Note 5
$Z_{RX\text{-}DC}$	DC Input Impedance	40	50	60	Ω	Required RX D+ as well as D– DC Impedance (50 ± 20% tolerance). See Notes 2 and 5.
$Z_{RX\text{-}HIGH\text{-}IMP\text{-}DC}$	Powered Down DC Input Impedance	200 k	—	—	Ω	Required RX D+ as well as D– DC Impedance when the Receiver terminations do not have power. See Note 6.
$V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p}$	Electrical Idle Detect Threshold	65	—	—	mV	$V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p} = 2*\lvert V_{RX\text{-}D+} - V_{RX\text{-}D-}\rvert$ Measured at the package pins of the Receiver

Table 57. Long Run Transmitter AC Timing Specifications—3.125 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output Voltage,	V_O	–0.40	2.30	Volts	Voltage relative to COMMON of either signal comprising a differential pair
Differential Output Voltage	V_{DIFFPP}	800	1600	mV p-p	—
Deterministic Jitter	J_D	—	0.17	UI p-p	—
Total Jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit Interval	UI	320	320	ps	+/– 100 ppm

For each baud rate at which an LP-Serial transmitter is specified to operate, the output eye pattern of the transmitter shall fall entirely within the unshaded portion of the Transmitter Output Compliance Mask shown in Figure 54 with the parameters specified in Table 58 when measured at the output pins of the device and the device is driving a 100 Ω +/–5% differential resistive load. The output eye pattern of an LP-Serial transmitter that implements pre-emphasis (to equalize the link and reduce inter-symbol interference) need only comply with the Transmitter Output Compliance Mask when pre-emphasis is disabled or minimized.

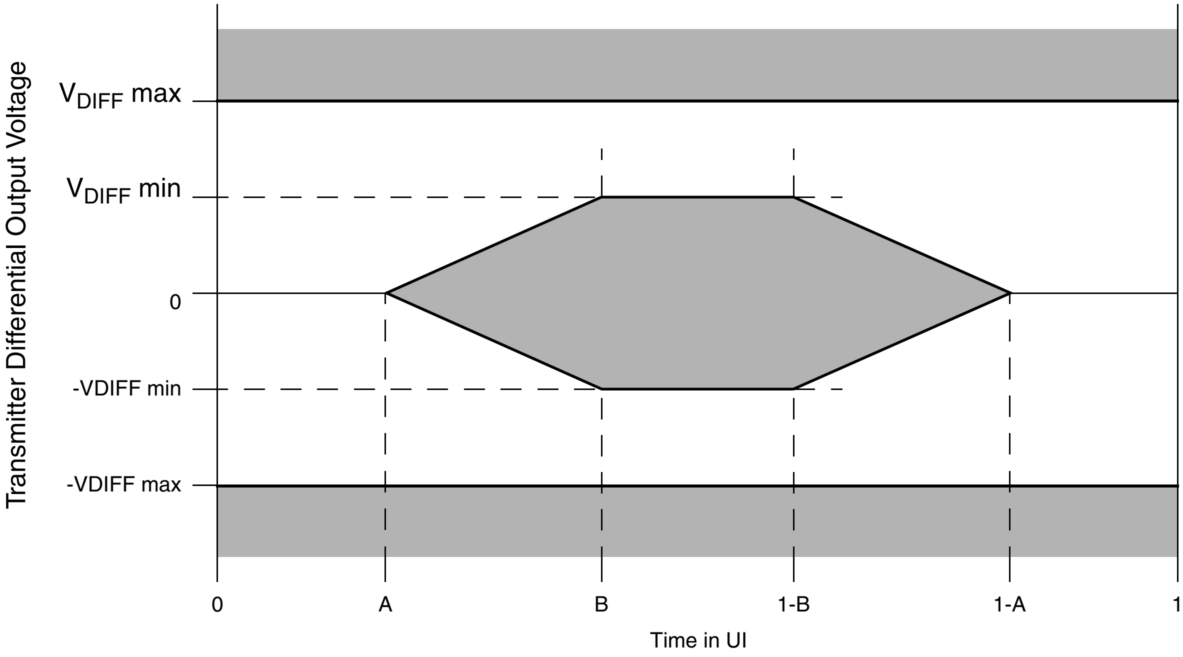


Figure 54. Transmitter Output Compliance Mask

Table 60. Receiver AC Timing Specifications—2.5 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential Input Voltage	V_{IN}	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total Jitter Tolerance[1]	J_T	0.65	—	UI p-p	Measured at receiver
Multiple Input Skew	S_{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	—	10^{-12}	—	—
Unit Interval	UI	400	400	ps	+/– 100 ppm

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of Figure 55. The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

Table 61. Receiver AC Timing Specifications—3.125 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential Input Voltage	V_{IN}	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total Jitter Tolerance[1]	J_T	0.65	—	UI p-p	Measured at receiver
Multiple Input Skew	S_{MI}	—	22	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	—	10^{-12}	—	—
Unit Interval	UI	320	320	ps	+/– 100 ppm

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of Figure 55. The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

16 Package

This section details package parameters and dimensions.

16.1 Package Parameters for the MPC8641

The package parameters are as provided in the following list. The package type is 33 mm × 33 mm, 1023 pins. There are two package options: high-lead Flip Chip-Ceramic Ball Grid Array (FC-CBGA), and lead-free (FC-CBGA).

For all package types:

Die size	12.1 mm × 14.7 mm
Package outline	33 mm × 33 mm
Interconnects	1023
Pitch	1 mm
Total Capacitor count	43 caps; 100 nF each

For high-lead FC-CBGA (package option: HCTE[1] HX)

Maximum module height	2.97 mm
Minimum module height	2.47 mm
Solder Balls	89.5% Pb 10.5% Sn
Ball diameter (typical[2])	0.60 mm

For RoHS lead-free FC-CBGA (package option: HCTE[1] VU) and lead-free FC-CBGA (package option: HCTE[1] VJ)

Maximum module height	2.77 mm
Minimum module height	2.27 mm
Solder Balls	95.5% Sn 4.0% Ag 0.5% Cu
Ball diameter (typical[2])	0.60 mm

[1] High-coefficient of thermal expansion

[2] Typical ball diameter is before reflow

8. Note that for MPC8641 (single core) the solder balls for the following signals/pins are not populated in the package: VDD_Core1 (R16, R18, R20, T17, T19, T21, T23, U16, U18, U22, V17, V19, V21, V23, W16, W18, W20, W22, Y17, Y19, Y21, Y23, AA16, AA18, AA20, AA22, AB23, AC24) and SENSEVDD_Core1 (U20).

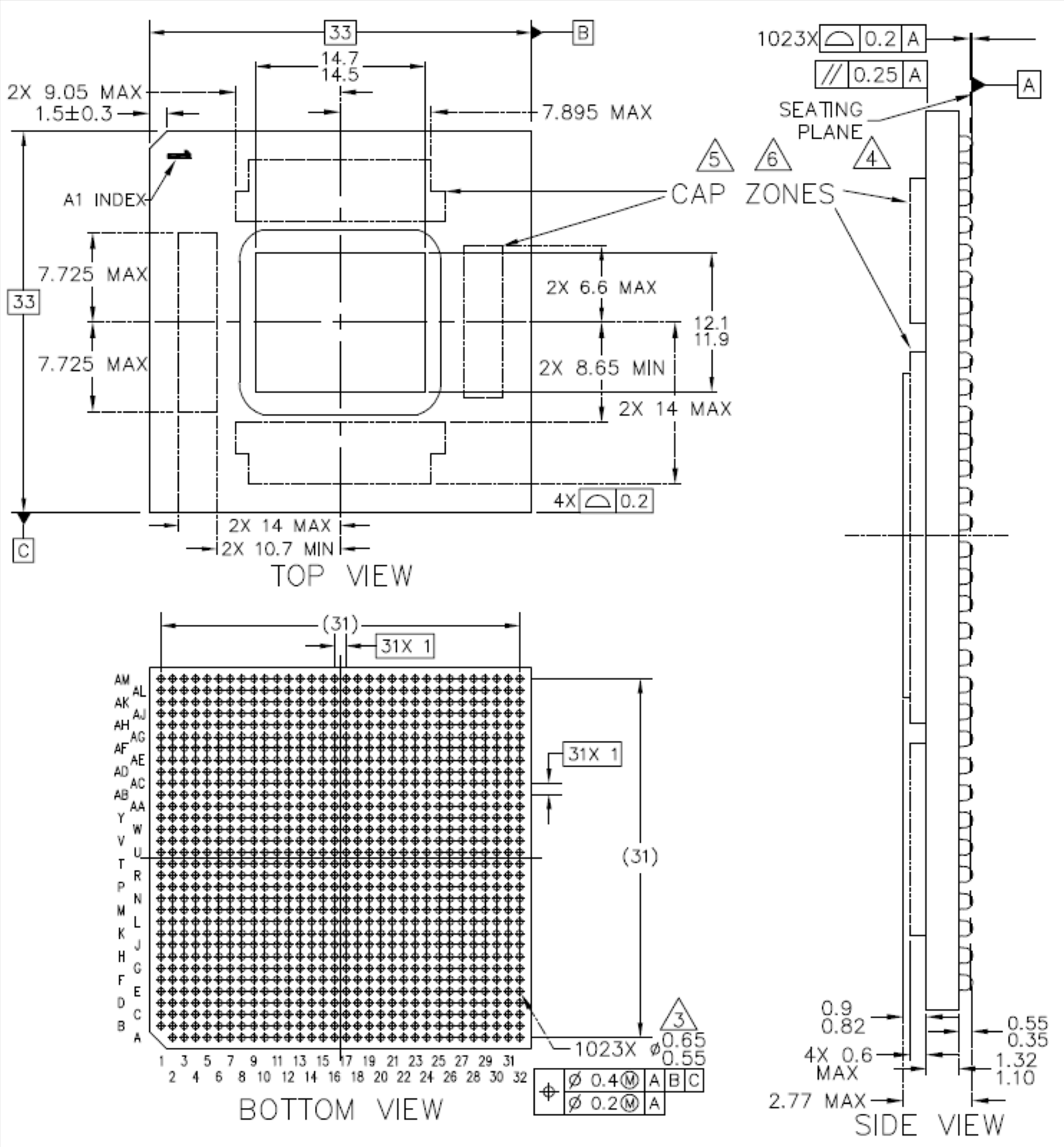


Figure 58. MPC8641D Lead-Free FC-CBGA Dimensions

NOTES for Figure 58

1. All dimensions are in millimeters.
2. Dimensions and tolerances per ASME Y14.5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is defined by the spherical crowns of the solder balls.
5. Capacitors may not be present on all devices.
6. Caution must be taken not to short capacitors or expose metal capacitor pads on package top.
7. All dimensions symmetrical about centerlines unless otherwise specified.
8. Note that for MPC8641 (single core) the solder balls for the following signals/pins are not populated in the package: VDD_Core1 (R16, R18, R20, T17, T19, T21, T23, U16, U18, U22, V17, V19, V21, V23, W16, W18, W20, W22, Y17, Y19, Y21, Y23, AA16, AA18, AA20, AA22, AB23, AC24) and SENSEVDD_Core1 (U20).

17 Signal Listings

Table 63 provides the pin assignments for the signals. Notes for the signal changes on the single core device (MPC8641) are italicized and prefixed by *"S"*.

Table 63. MPC8641 Signal Reference by Functional Block

Name[1]	Package Pin Number	Pin Type	Power Supply	Notes
DDR Memory Interface 1 Signals[2,3]				
D1_MDQ[0:63]	D15, A14, B12, D12, A15, B15, B13, C13, C11, D11, D9, A8, A12, A11, A9, B9, F11, G12, K11, K12, E10, E9, J11, J10, G8, H10, L9, L7, F10, G9, K9, K8, AC6, AC7, AG8, AH9, AB6, AB8, AE9, AF9, AL8, AM8, AM10, AK11, AH8, AK8, AJ10, AK10, AL12, AJ12, AL14, AM14, AL11, AM11, AM13, AK14, AM15, AJ16, AK18, AL18, AJ15, AL15, AL17, AM17	I/O	D1_GV$_{DD}$	—
D1_MECC[0:7]	M8, M7, R8, T10, L11, L10, P9, R10	I/O	D1_GV$_{DD}$	—
D1_MDM[0:8]	C14, A10, G11, H9, AD7, AJ9, AM12, AK16, N10	O	D1_GV$_{DD}$	—
D1_MDQS[0:8]	A13, C10, H12, J7, AE8, AM9, AK13, AK17, N9	I/O	D1_GV$_{DD}$	—
$\overline{\text{D1\_MDQS}}$[0:8]	D14, B10, H13, J8, AD8, AL9, AJ13, AM16, P10	I/O	D1_GV$_{DD}$	—
D1_MBA[0:2]	AA8, AA10, T9	O	D1_GV$_{DD}$	—
D1_MA[0:15]	Y10, W8, W9, V7, V8, U6, V10, U9, U7, U10, Y9, T6, T8, AE12, R7, P6	O	D1_GV$_{DD}$	—
$\overline{\text{D1\_MWE}}$	AB11	O	D1_GV$_{DD}$	—
$\overline{\text{D1\_MRAS}}$	AB12	O	D1_GV$_{DD}$	—
$\overline{\text{D1\_MCAS}}$	AC10	O	D1_GV$_{DD}$	—
$\overline{\text{D1\_MCS}}$[0:3]	AB9, AD10, AC12, AD11	O	D1_GV$_{DD}$	—
D1_MCKE[0:3]	P7, M10, N8, M11	O	D1_GV$_{DD}$	23
D1_MCK[0:5]	W6, E13, AH11, Y7, F14, AG10	O	D1_GV$_{DD}$	—
$\overline{\text{D1\_MCK}}$[0:5]	Y6, E12, AH12, AA7, F13, AG11	O	D1_GV$_{DD}$	—
D1_MODT[0:3]	AC9, AF12, AE11, AF10	O	D1_GV$_{DD}$	—
D1_MDIC[0:1]	E15, G14	IO	D1_GV$_{DD}$	27
D1_MV$_{REF}$	AM18	DDR Port 1 reference voltage	D1_GV$_{DD}$ /2	3
DDR Memory Interface 2 Signals[2,3]				

Table 63. MPC8641 Signal Reference by Functional Block (continued)

Name[1]	Package Pin Number	Pin Type	Power Supply	Notes
SD1_PLL_TPA	T28	Analog	SV$_{DD}$	13, 18
SD1_DLL_TPD	N28	O	SV$_{DD}$	13, 17
SD1_DLL_TPA	P31	Analog	SV$_{DD}$	13, 18
High Speed I/O Interface 2 (SERDES 2)[4]				
SD2_TX[0:3]	Y24, AA27, AB25, AC27	O	SV$_{DD}$	—
SD2_TX[4:7]	AE27, AG27, AJ27, AL27	O	SV$_{DD}$	34
$\overline{\text{SD2\_TX}}$[0:3]	Y25, AA28, AB26, AC28	O	SV$_{DD}$	—
$\overline{\text{SD2\_TX}}$[4:7]	AE28, AG28, AJ28, AL28	O	SV$_{DD}$	34
SD2_RX[0:3]	Y30, AA32, AB30, AC32	I	SV$_{DD}$	32
SD2_RX[4:7]	AH30, AJ32, AK30, AL32	I	SV$_{DD}$	32, 35
$\overline{\text{SD2\_RX}}$[0:3]	Y29, AA31, AB29, AC31	I	SV$_{DD}$	—
$\overline{\text{SD2\_RX}}$[4:7]	AH29, AJ31, AK29, AL31	I	SV$_{DD}$	35
SD2_REF_CLK	AE32	I	SV$_{DD}$	—
$\overline{\text{SD2\_REF\_CLK}}$	AE31	I	SV$_{DD}$	—
SD2_IMP_CAL_TX	AM29	Analog	SV$_{DD}$	19
SD2_IMP_CAL_RX	AA26	Analog	SV$_{DD}$	30
SD2_PLL_TPD	AF29	O	SV$_{DD}$	13, 17
SD2_PLL_TPA	AF31	Analog	SV$_{DD}$	13, 18
SD2_DLL_TPD	AD29	O	SV$_{DD}$	13, 17
SD2_DLL_TPA	AD30	Analog	SV$_{DD}$	13, 18
Special Connection Requirement pins				
No Connects	K24, K25, P28, P29, W26, W27, AD25, AD26	—	—	13
Reserved	H30, R32, V28, AG32	—	—	14
Reserved	H29, R31, W28, AG31	—	—	15
Reserved	AD24, AG26	—	—	16
Ethernet Miscellaneous Signals[5]				
EC1_GTX_CLK125	AL23	I	LV$_{DD}$	39
EC2_GTX_CLK125	AM23	I	TV$_{DD}$	39
EC_MDC	G31	O	OV$_{DD}$	—
EC_MDIO	G32	I/O	OV$_{DD}$	—
eTSEC Port 1 Signals[5]				

Table 63. MPC8641 Signal Reference by Functional Block (continued)

Name[1]	Package Pin Number	Pin Type	Power Supply	Notes

Note:

1. Multi-pin signals such as D1_MDQ[0:63] and D2_MDQ[0:63] have their physical package pin numbers listed in order corresponding to the signal names.
2. Stub Series Terminated Logic (SSTL-18 and SSTL-25) type pins.
3. If a DDR port is not used, it is possible to leave the related power supply (Dn_GVDD, Dn_MVREF) turned off at reset. Note that these power supplies can only be powered up again at reset for functionality to occur on the DDR port.
4. Low Voltage Differential Signaling (LVDS) type pins.
5. Low Voltage Transistor-Transistor Logic (LVTTL) type pins.
6. This pin is a reset configuration pin and appears again in the Reset Configuration Signals section of this table. See the Reset Configuration Signals section of this table for config name and connection details.
7. Recommend a weak pull-up resistor (1–10 kΩ) be placed from this pin to its power supply.
8. Recommend a weak pull-down resistor (2–10 kΩ) be placed from this pin to ground.
9. This multiplexed pin has input status in one mode and output in another
10. This pin is a multiplexed signal for different functional blocks and appears more than once in this table.
11. This pin is open drain signal.
12. Functional only on the MPC8641D.
13. These pins should be left floating.
14. These pins should be connected to SV_{DD}.
15. These pins should be pulled to ground with a strong resistor (270-Ω to 330-Ω).
16. These pins should be connected to OVDD.
17. This is a SerDes PLL/DLL digital test signal and is only for factory use.
18. This is a SerDes PLL/DLL analog test signal and is only for factory use.
19. This pin should be pulled to ground with a 100-Ω resistor.
20. The pins in this section are reset configuration pins. Each pin has a weak internal pull-up P-FET which is enabled only when the processor is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7-kΩ pull-down resistor. However, if the signal is intended to be high after reset, and if there is any device on the net which might pull down the value of the net at reset, then a pullup or active driver is needed.
21. Should be pulled down at reset if platform frequency is at 400 MHz.
22. These pins require 4.7-kΩ pull-up or pull-down resistors and must be driven as they are used to determine PLL configuration ratios at reset.
23. This output is actively driven during reset rather than being tri-stated during reset.
24 These JTAG pins have weak internal pull-up P-FETs that are always enabled.
25. This pin should NOT be pulled down (or driven low) during reset.
26. These are test signals for factory use only and must be pulled up (100-Ω to 1- kΩ.) to OVDD for normal machine operation.
27. Dn_MDIC[0] should be connected to ground with an 18-Ω resistor +/– 1-Ω and Dn_MDIC[1] should be connected Dn_GVDD with an 18-Ω resistor +/– 1-Ω. These pins are used for automatic calibration of the DDR IOs.
28. Pin N18 is recommended as a reference point for determining the voltage of V_{DD}_PLAT and is hence considered as the V_{DD}_PLAT sensing voltage and is called SENSEVDD_PLAT.
29. Pin P18 is recommended as the ground reference point for SENSEVDD_PLAT and is called SENSEVSS_PLAT.
30. This pin should be pulled to ground with a 200-Ω resistor.
31. These pins are connected to the power/ground planes internally and may be used by the core power supply to improve tracking and regulation.
32. Must be tied low if unused
33. These pins may be used as defined functional reset configuration pins in the future. Please include a resistor pull up/down option to allow flexibility of future designs.
34. Used as serial data output for SRIO 1x/4x link.
35. Used as serial data input for SRIO 1x/4x link.
36. This pin requires an external 4.7-kΩ pull-down resistor to pevent PHY from seeing a valid Transmit Enable before it is actively driven.

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